

The SR45P10DL uses advanced SGT technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. The package form is TO-252, which accords with the ROHS standard and Halogen Free standard.

Features:

- Fast Switching
- Low Gate Charge and $R_{DS(ON)}$
- Low Reverse transfer capacitances

Applications:

- DC-DC converter
- Portable Equipment
- Power management



Package Marking and Ordering Information:

Marking	Part #	Package	Packing
SR45P10DL	SR45P10DL	TO-252	Reel

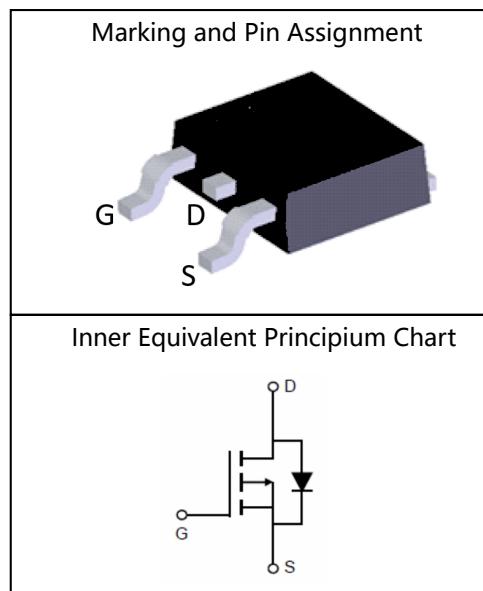
Absolute Maximum Ratings:

Symbol	Parameter	Value	Units
V_{DSS}	Drain-to-Source Voltage	-100	V
I_D	Continuous Drain Current	-28	A
	Continuous Drain Current	- 16.5	A
I_{DM}^a	Pulsed Drain Current	-105	A
E_{AS}^a	Single pulse avalanche energy	225	mJ
I_{AR}	Single pulse avalanche current	30	A
V_{GS}	Gate-to-Source Voltage	±20	V
P_D	Power Dissipation	120	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	°C
T_L	Maximum Temperature for Soldering	260	°C

Thermal Characteristics:

Symbol	Parameter	Value	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	50	°C/W

Silicon P-Channel Power MOSFET



Electrical Characteristics (TA = 25°C unless otherwise specified):

Static Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =-250μA	-100	--	--	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =-100V, V _{GS} =0V	--	--	1	μA
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =-20V, V _{DS} =0V	--	--	100	nA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =+20V, V _{DS} =0V	--	--	-100	nA
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250μA	-1.0	-1.5	-2.5	V
R _{DSON1}	Drain-to-Source On-Resistance	V _{GS} =-10V, I _D =-20A	--	46	58	mΩ
R _{DSON2}	Drain-to-Source On-Resistance	V _{GS} =-4.5V, I _D =-10A	--	55	65	mΩ
g _{FS}	Forward Transconductance	V _{DS} =-5V, I _D =-20A	--	20	--	S

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
C _{iss}	Input Capacitance	V _{GS} = 0V V _{DS} = -50V f = 1.0MHz	--	2100	--	pF
C _{oss}	Output Capacitance		--	168	--	
C _{rss}	Reverse Transfer Capacitance		--	26	--	
R _g	Gate resistance	V _{GS} = 0V, V _{DS} Open	--	2.8	--	Ω

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D = -20A V _{DS} = -50V V _{GS} = -10V R _G = 5Ω	--	8.2	--	ns
t _r	Rise Time		--	19.6	--	
t _{d(OFF)}	Turn-Off Delay Time		--	62.8	--	
t _f	Fall Time		--	41.4	--	
Q _g	Total Gate Charge	V _{GS} = -10V V _{DS} = -50V I _D = -20A	--	38	--	nC
Q _{gs}	Gate Source Charge		--	6.4	--	
Q _{gd}	Gate Drain Charge		--	6.8	--	

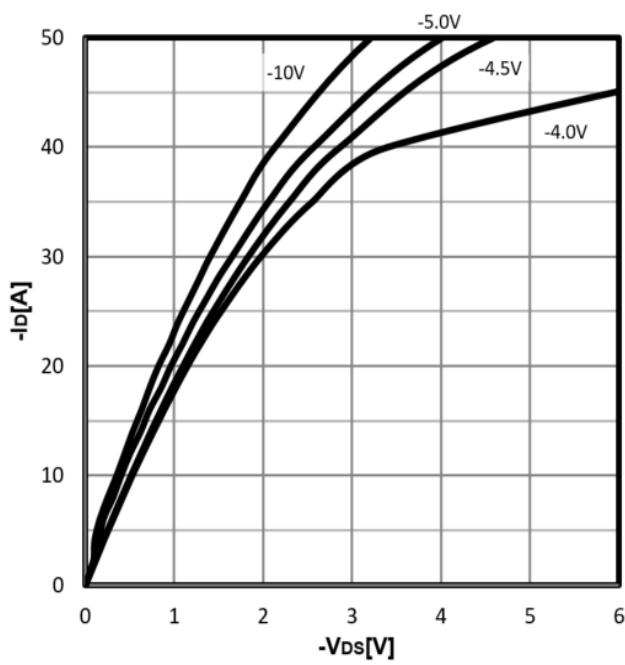
Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
V _{SD}	Diode Forward Voltage	I _S =-20A, V _{GS} =0V	--	--	1.2	V
t _{rr}	Reverse Recovery time	I _S =-20A, V _{DD} =-50V	--	68	--	ns
Q _{rr}	Reverse Recovery Charge	di/dt=100A/μs	--	200	--	nC

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

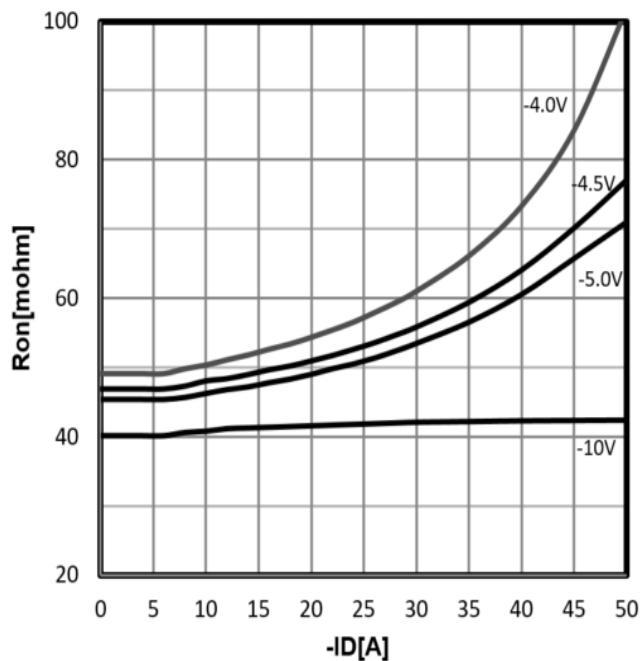
^{a2}: V_{DD}=-50V, L=0.5mH, R_g=25Ω, Starting T_J=25 °C

Characteristics Curve:

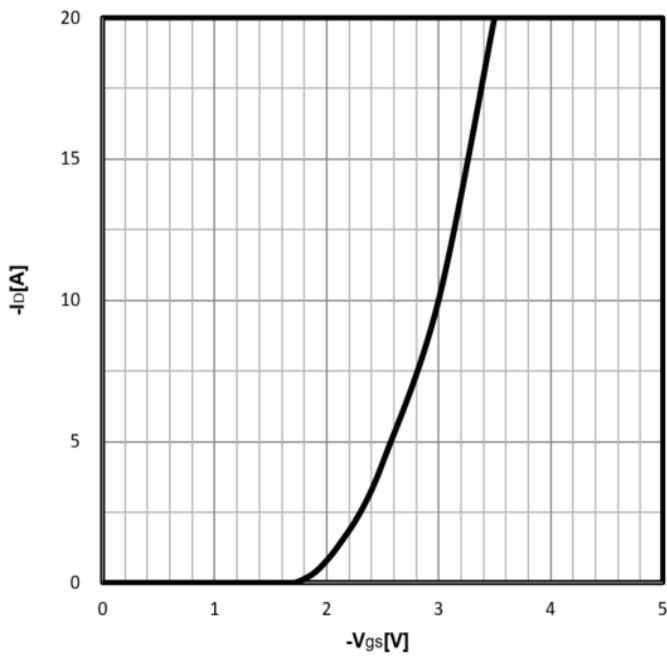
Typ. output characteristics
 $-I_D = f(-V_{DS})$



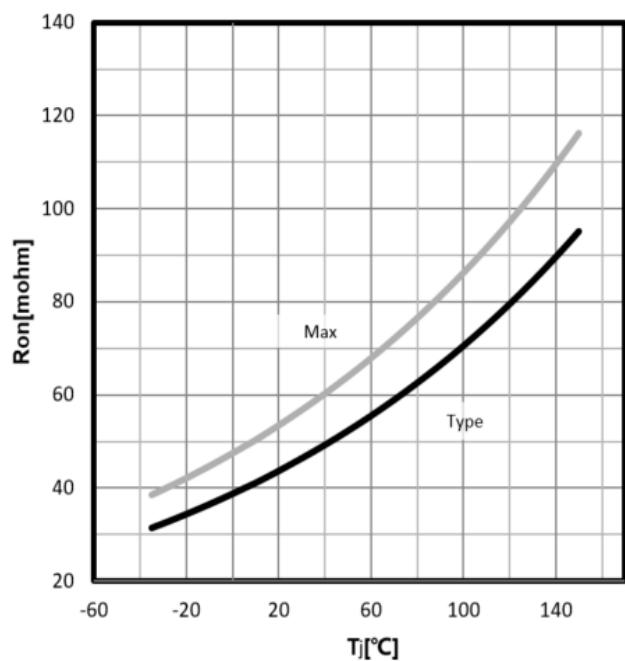
Typ. drain-source on resistance
 $R_{DS(on)} = f(-I_D)$



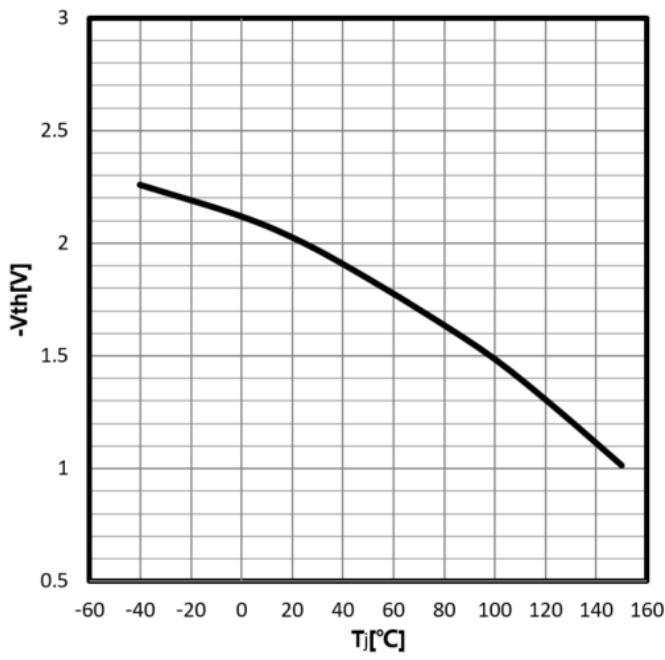
Typ. transfer characteristics
 $-I_D = f(-V_{GS})$



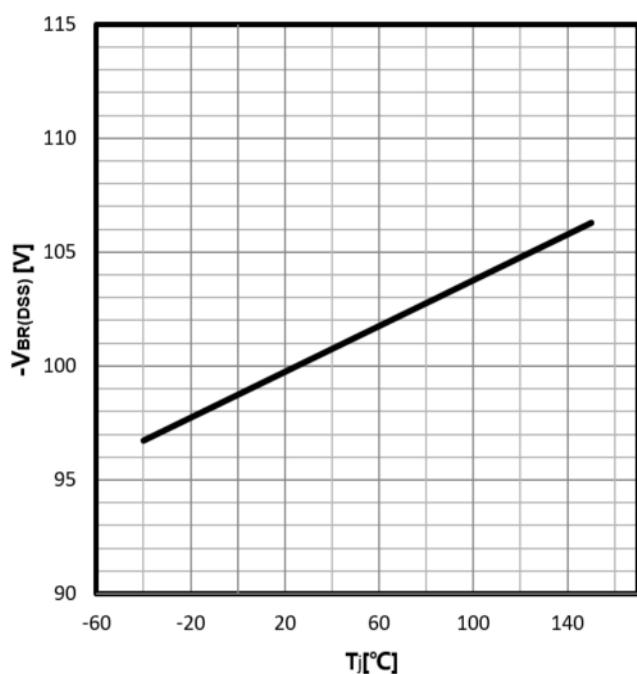
Drain-source on-state resistance
 $R_{DS(on)} = f(T_j); I_D = -20A; V_{GS} = -10V$



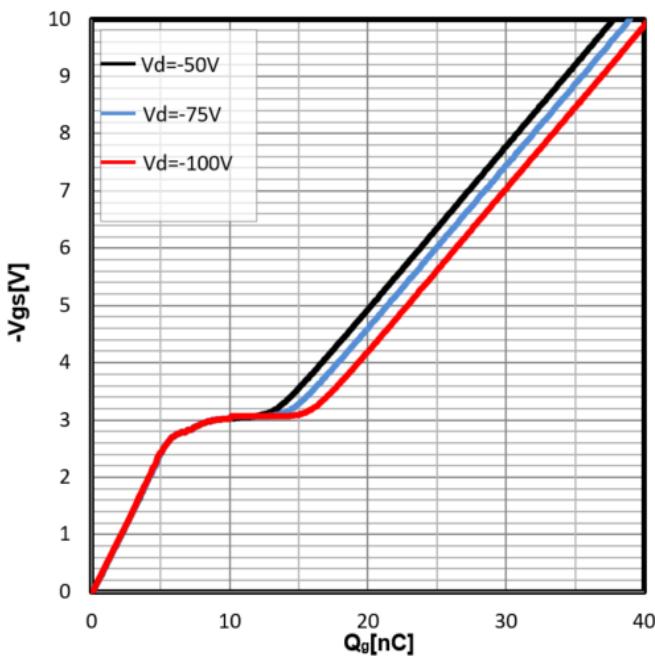
Gate Threshold Voltage
 $-V_{TH} = f(T_j); I_D = -250\mu A$



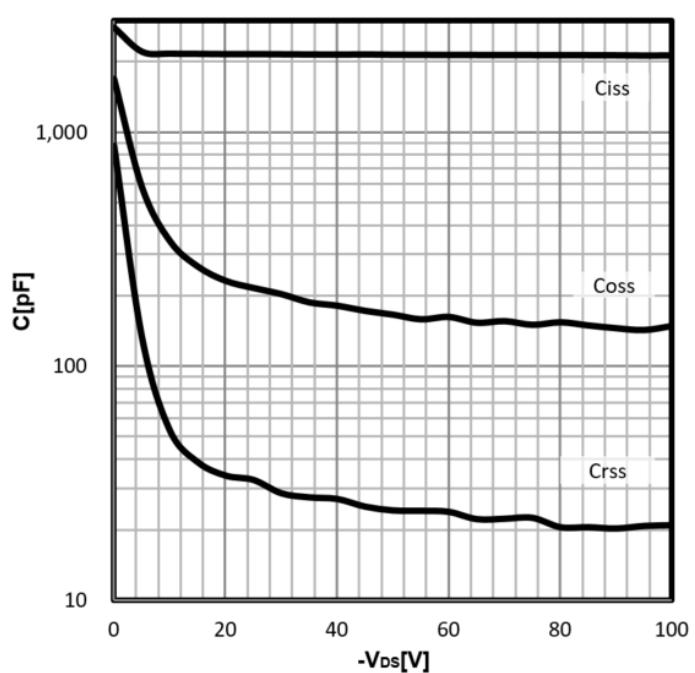
Drain-source breakdown voltage
 $-V_{BR(DSS)} = f(T_j); I_D = -250\mu A$



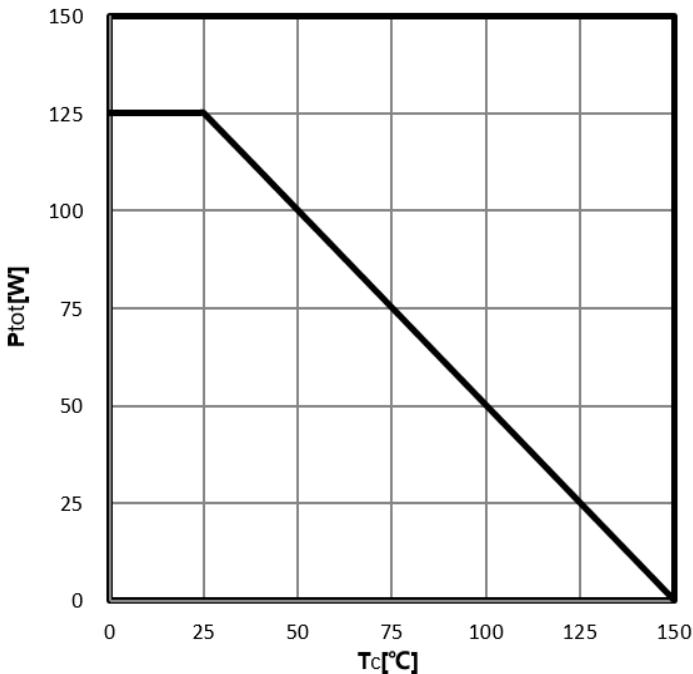
Typ. gate charge
 $-V_{GS} = f(Q_g); I_D = -20A$



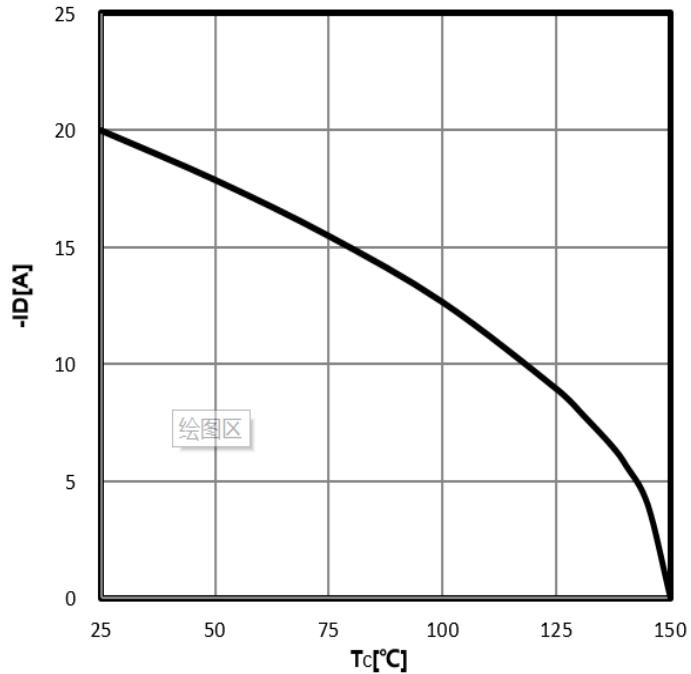
Typ. capacitances
 $C = f(-V_{DS}); V_{GS} = 0V; f = 1MHz$



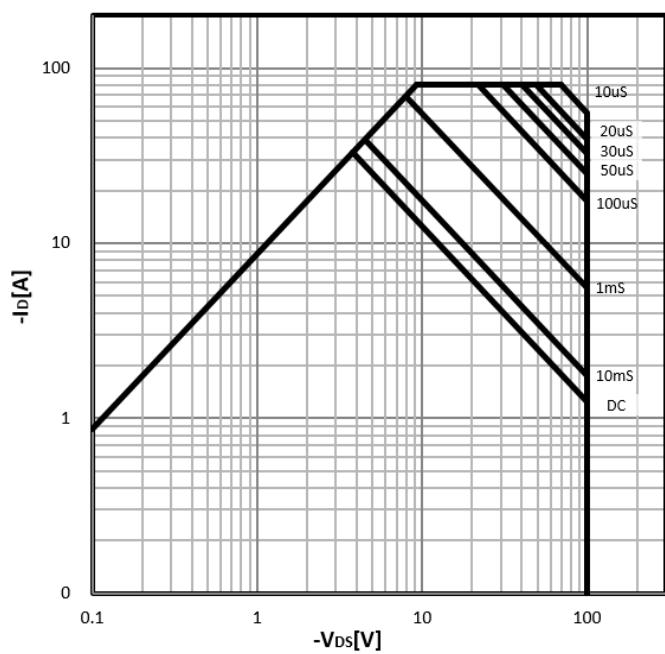
Power Dissipation
 $P_{tot}=f(T_C)$



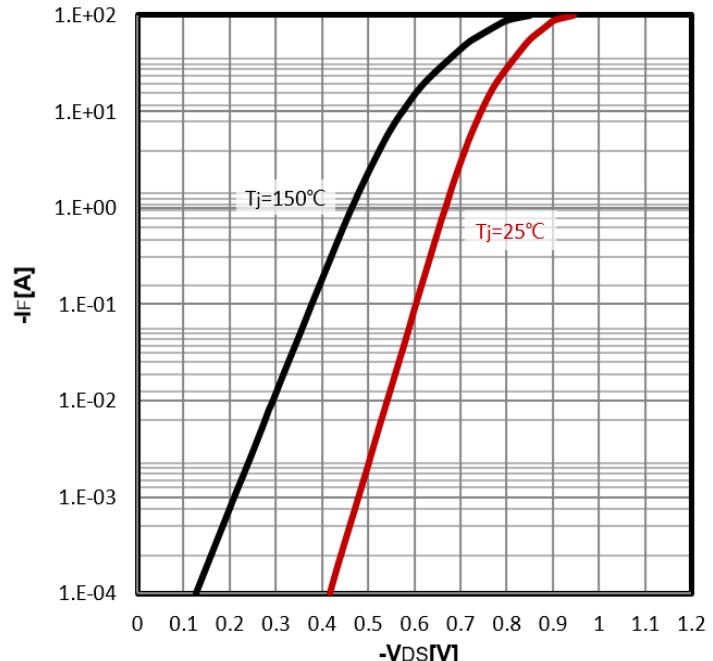
Maximum Drain Current
 $-I_D=f(T_C)$



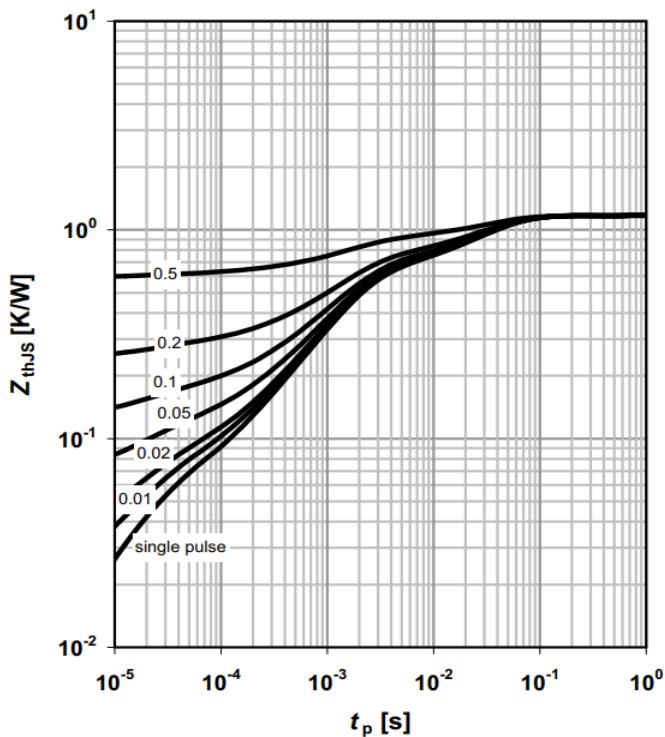
Safe operating area
 $-I_D=f(-V_{DS})$

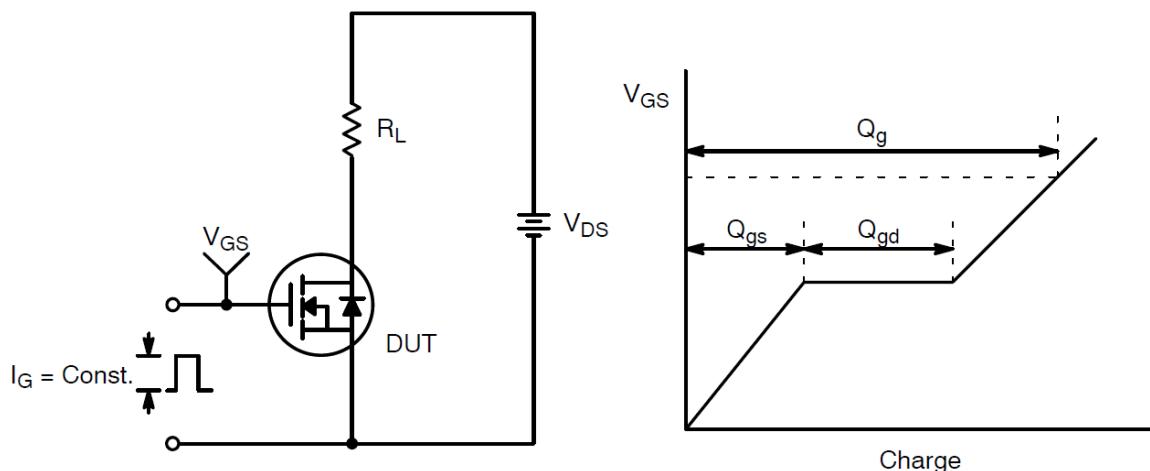
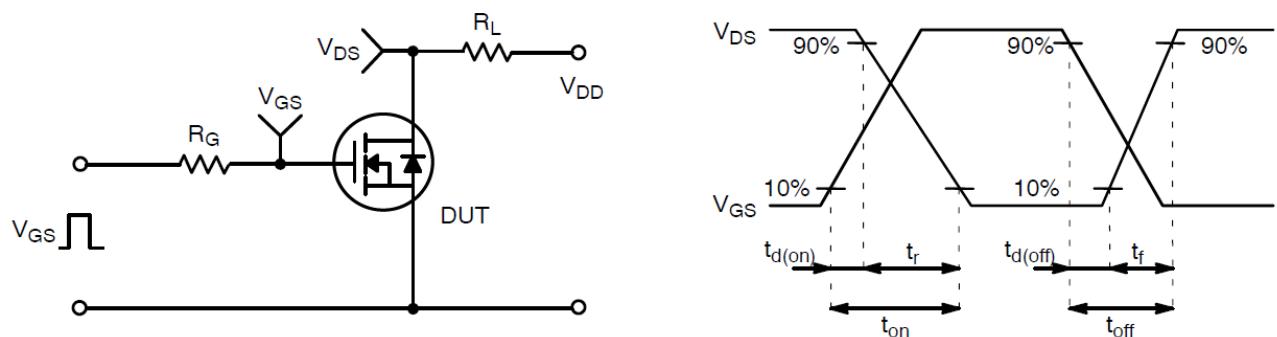
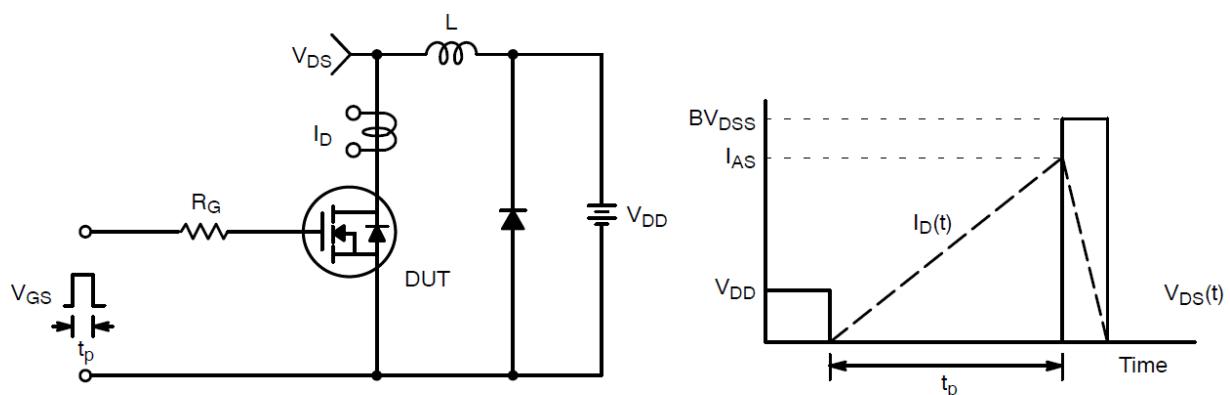


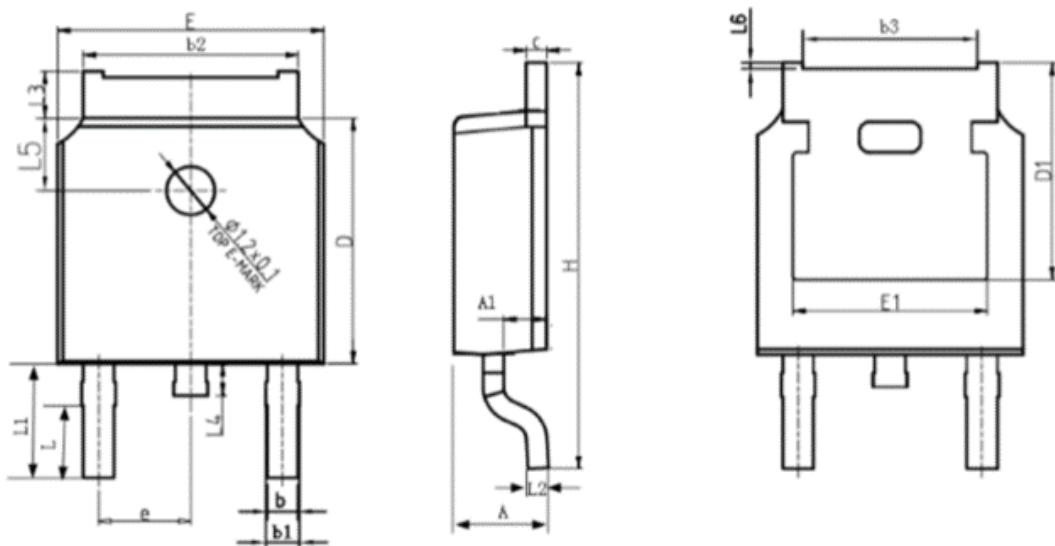
Body Diode Forward Voltage Variation
 $-I_F=f(-V_{DS})$



Max. transient thermal impedance
 $Z_{thJC} = f(t_p)$



Test Circuit and Waveform:

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching Test Circuit & Waveforms

Package Information:


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.056	0.061
A1	0.970	1.17	0.025	0.030
b	0.720	0.850	0.018	0.022
b1	0.720	0.930	0.018	0.024
b2	5.230	5.460	0.133	0.139
b3	4.270	4.370	0.108	0.111
c	0.470	0.580	0.012	0.015
D	6.000	6.200	0.152	0.157
D1	5.300 TYP.		0.135	
E	6.500	6.700	0.165	0.170
E1	4.700	4.920	0.119	0.125
e	2.286 TYP		0.058	
L	1.400	1.700	0.036	0.043
L1	2.900 TYP.		0.074	
L2	0.510 TYP.		0.013	
L3	0.900	1.250	0.023	0.032
L4	0.600	1.000	0.015	0.025
L5	1.700	1.900	0.043	0.048
L6	0	0.1223	0.000	0.003



SR45P10DL

产品名称: SR45P10DL

文档类型: 说明书

版 权: 意盛微(上海)电子有限公司

公司主页: WWW.SXCAI.COM

版 本: 1.0

修改记录:

1. 原本

版 本: 2.0

修改记录:

1. 更改ID电流 , RDS(ON)
